

# STD30NF06L

# N-CHANNEL 60V - 0.022Ω - 35A DPAK/IPAK STripFET™ POWER MOSFET

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STD30NF06L	60 V	<0.028Ω	35 A

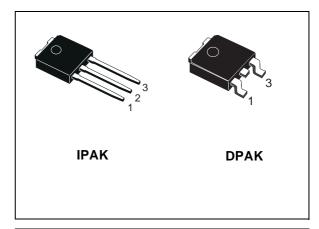
- TYPICAL  $R_{DS}(on) = 0.022\Omega$
- EXCEPTIONAL dv/dt CAPABILITY
- LOGIC LEVEL GATE DRIVE
- ADD SUFFIX "T4" FOR ORDERING IN TAPE & REEL
- ADD SUFFIX "-1" FOR ORDERING IN IPAK
- CHARACTERIZATION ORIENTED FOR AUTOMOTIVE APPLICATIONS

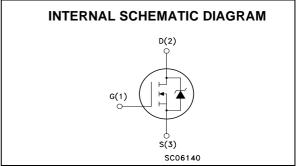


This Power Mosfet is the latest development of STMicroelectronics unique "Single Feature Size<sup>TM</sup>" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalance characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.



- HIGH-EFFICIENCY DC-DC CONVERTERS
- MOTOR CONTROL, AUDIO AMPLIFIERS
- DC-DC & DC-AC CONVERTERS
- AUTOMOTIVE





#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	60	V
V <sub>DGR</sub>	Drain-gate Voltage (R <sub>GS</sub> = 20 k $\Omega$ )	60	V
V <sub>GS</sub>	Gate- source Voltage	± 20	V
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 25°C	35	А
I <sub>D</sub>	Drain Current (continuous) at T <sub>C</sub> = 100°C	25	А
I <sub>DM</sub> (●)	Drain Current (pulsed)	140	А
P <sub>TOT</sub>	Total Dissipation at T <sub>C</sub> = 25°C	70	W
	Derating Factor	0.46	W/°C
dv/dt (1)	Peak Diode Recovery voltage slope	25	V/ns
T <sub>stg</sub>	Storage Temperature	– 55 to 175	°C
Tj	Operating Junction Temperature	- 33 10 17 3	

( Pulse width limited by safe operating area

(1) I<sub>SD</sub>  $\leq$ 38A, di/dt  $\leq$ 400A/ $\mu$ s, V<sub>DD</sub>  $\leq$  V(BR)DSS, T $_{j}$   $\leq$  T<sub>JMAX</sub>.

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#### STD30NF06L

#### THERMAL DATA

Ī	Rthj-case Thermal Resistance Junction-case Max		2.14	°C/W
Ī	Rthj-amb	Thermal Resistance Junction-ambient Max	100	°C/W
	$T_I$	Maximum Lead Temperature For Soldering Purpose	275	°C

#### **AVALANCHE CHARACTERISTICS**

Symbol	Parameter	Max Value	Unit
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T <sub>j</sub> max)	35	А
E <sub>AS</sub>	Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	150	mJ

# **ELECTRICAL CHARACTERISTICS** (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	60			V
I <sub>DSS</sub>	Zero Gate Voltage	V <sub>DS</sub> = Max Rating			1	μA
	Drain Current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max Rating, T <sub>C</sub> = 125 °C			10	μΑ
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 20 V			±100	nA

### ON (1)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	1.7	2.5	V
R <sub>DS(on)</sub>	Static Drain-source On	V <sub>GS</sub> = 5 V, I <sub>D</sub> = 18 A		0.025	0.03	Ω
	Resistance	$V_{GS} = 10 \text{ V}, I_D = 18 \text{ A}$		0.022	0.028	Ω

#### **DYNAMIC**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (1)	Forward Transconductance	$V_{DS} > =15 \text{ V}, I_{D} =15 \text{ A}$		25		S
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz, V}_{GS} = 0$		1600		pF
Coss	Output Capacitance			215		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			60		pF

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#### **ELECTRICAL CHARACTERISTICS** (CONTINUED)

#### **SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DD</sub> = 30 V, I <sub>D</sub> = 18 A		30		ns
t <sub>r</sub>	Rise Time	$R_G = 4.7\Omega V_{GS} = 4.5 V$ (see test circuit, Figure 3)		105		ns
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V <sub>DD</sub> = 48 V, I <sub>D</sub> = 38 A, V <sub>GS</sub> = 5 V		23 7 10	31	nC nC nC

#### **SWITCHING OFF**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(off)</sub>	Turn-off-Delay Time Fall Time	$V_{DD} = 30 \text{ V}, I_{D} = 18 \text{ A},$ $R_{G} = 4.7\Omega, V_{GS} = 4.5 \text{ V}$		65 25		ns ns
		(see test circuit, Figure 3)		-		

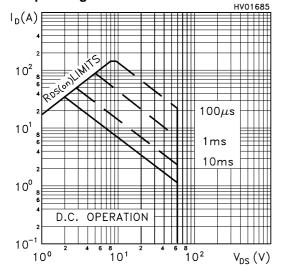
#### SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain Current				35	Α
I <sub>SDM</sub> (2)	Source-drain Current (pulsed)				140	Α
V <sub>SD</sub> (1)	Forward On Voltage	$I_{SD} = 35 \text{ A}, V_{GS} = 0$			1.5	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD}$ = 38 A, di/dt = 100 A/ $\mu$ s, $V_{DD}$ = 15 V, $T_j$ = 150°C (see test circuit, Figure 5)		70 140 4		ns nC A

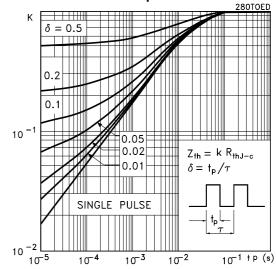
Note: 1. Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %.

Pulse width limited by safe operating area.

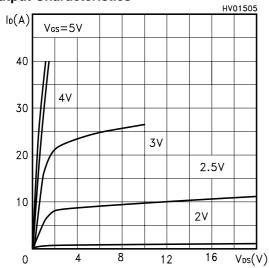
#### **Safe Operating Area**



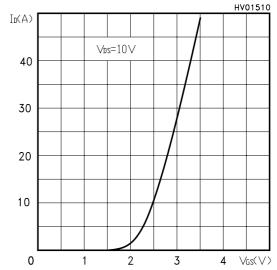
#### **Normalized Thermal Impedence**



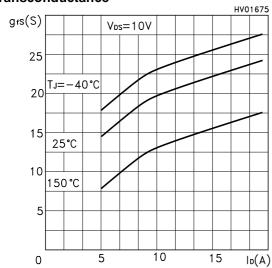
#### **Output Characteristics**



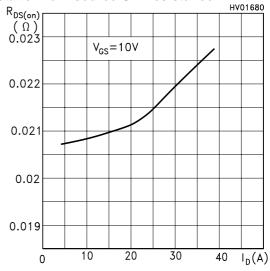
#### **Transfer Characteristics**

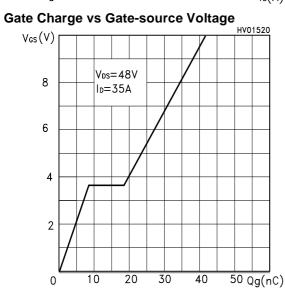


#### **Transconductance**

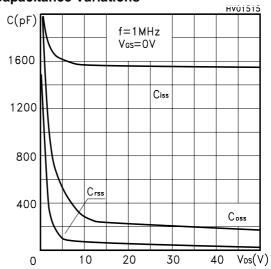


#### **Static Drain-source On Resistance**



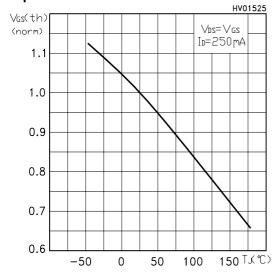


#### **Capacitance Variations**

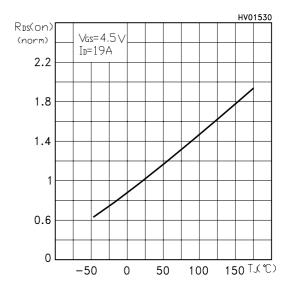


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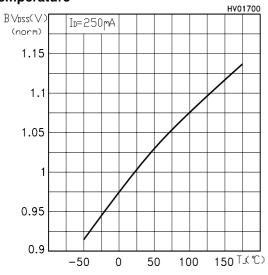
# Normalized Gate Threshold Voltage vs Temperature



#### **Normalized On Resistance vs Temperature**



# Normalized Drain-Source Breakdown vs Temperature



#### **Source-drain Diode Forward Characteristics**

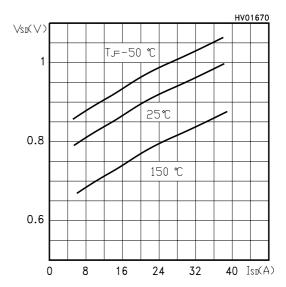
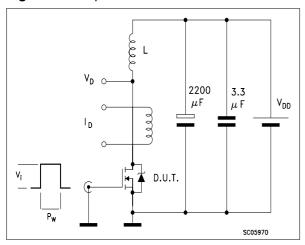


Fig. 1: Unclamped Inductive Load Test Circuit



**Fig. 3:** Switching Times Test Circuit For Resistive Load

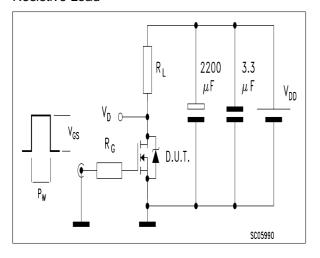


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

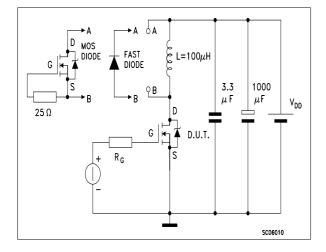


Fig. 2: Unclamped Inductive Waveform

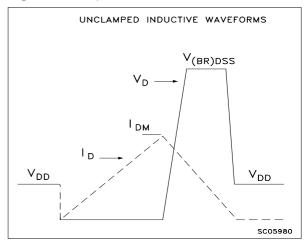
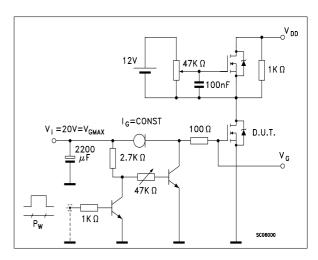
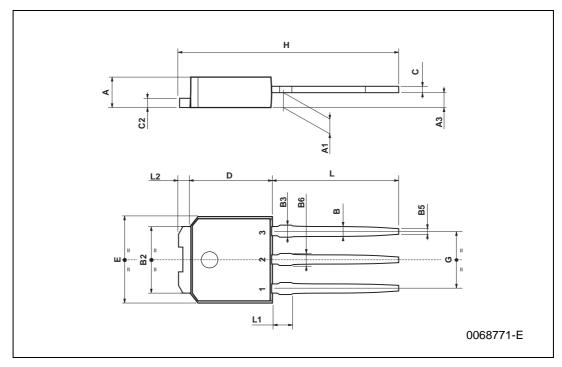


Fig. 4: Gate Charge test Circuit



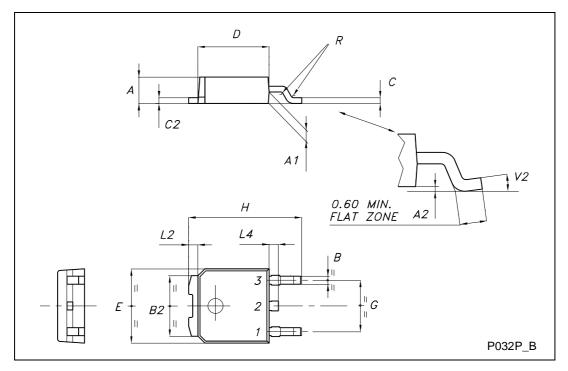
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DIM.		mm	inch			
DIN.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
В3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
Е	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



### **TO-252 (DPAK) MECHANICAL DATA**

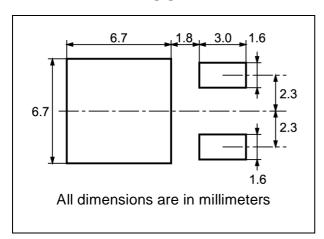
DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.20		2.40	0.087		0.094
A1	0.90		1.10	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.90	0.025		0.035
B2	5.20		5.40	0.204		0.213
С	0.45		0.60	0.018		0.024
C2	0.48		0.60	0.019		0.024
D	6.00		6.20	0.236		0.244
Е	6.40		6.60	0.252		0.260
G	4.40		4.60	0.173		0.181
Н	9.35		10.10	0.368		0.398
L2		0.8			0.031	
L4	0.60		1.00	0.024		0.039
V2	0°		8°	0°		0°

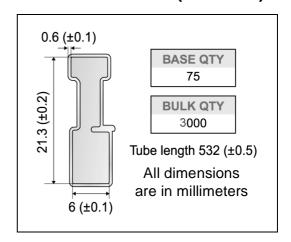


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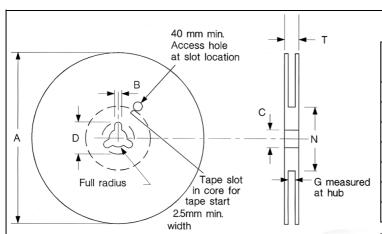
#### **DPAK FOOTPRINT**

## TUBE SHIPMENT (no suffix)\*





## TAPE AND REEL SHIPMENT (suffix "T4")\*

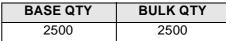


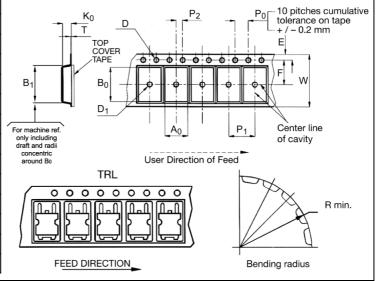
#### REEL MECHANICAL DATA

DIM.	m	m	inch	
Dilvi.	MIN.	MAX.	MIN.	MAX.
Α		330		12.992
В	1.5		0.059	
С	12.8	13.2	0.504	0.520
D	20.2		0.795	
G	16.4	18.4	0.645	0.724
N	50		1.968	
Т		22.4		0.881

#### TAPE MECHANICAL DATA

	m	m	inch		
DIM.	MIN.	MAX.	MIN.	MAX.	
A0	6.8	7	0.267	0.275	
В0	10.4	10.6	0.409	0.417	
B1		12.1		0.476	
D	1.5	1.6	0.059	0.063	
D1	1.5		0.059		
Е	1.65	1.85	0.065	0.073	
F	7.4	7.6	0.291	0.299	
K0	2.55	2.75	0.100	0.108	
P0	3.9	4.1	0.153	0.161	
P1	7.9	8.1	0.311	0.319	
P2	1.9	2.1	0.075	0.082	
R	40		1.574		
W	15.7	16.3	0.618	0.641	





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